Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,110	SUNAOSHI, TAKAMITSU	J
Examiner	Art Unit	
Crystal J. Barnes	2121	

	SEARCHED		
Class	Subclass	Date	Examiner
700	3, 9, 13, 40, 56, 57, 61, 62	7/29/2005	CJB
700	65-67	7/29/2005	CJB
700	69, 70	7/29/2005	CJB
700	75, 169	7/29/2005	CJB
700	172, 177	7/29/2005	CJB
700	178, 186	7/29/2005	CJB
700	190, 192	7/29/2005	CJB
700	193, 302	7/29/2005	CJB
700	245-250	7/29/2005	CJB
700	253, 262	7/29/2005	CJB
702	150-154	7/29/2005	CJB
709	208-211	7/29/2005	CJB
318	566,568.2	7/29/2005	CJB
318	568.11	7/29/2005	СЈВ

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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see abov	e search	7/29/2005	CJB	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Text Search (see attached)	7/29/2005	CJB	
Inventor Name Search	7/29/2005	CJB	

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318	568.16	7/29/2005	CJB	
318	568.17	7/29/2005	CJB	
318	568.22	7/29/2005	CJB	
318	568.21	7/29/2005	CJB	
600	102, 429	7/29/2005	CJB	
901	6, 9	7/29/2005	CJB	
901	30-32	7/29/2005	CJB	
901	36, 41	7/29/2005	CJB	
606	1	7/29/2005	CJB	
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INTERFERENCE SEARCHED		
Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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